

EAST Search History

10/666,770

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	boundary scan test receiver\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:54
L2	3	boundary scan test receiver\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L3	405475	comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L4	2	I2 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L5	27	programmable hysteresis circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L6	2	I4 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:13
L7	181868	reference voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L8	996	voltage hysteresis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56

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L9	403	I8 and I7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L10	5	I9 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:06
L11	2	I10 and I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:13
L12	2	I11 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L16	1	("IEEE 1149.6") and (boundary scan test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L17	4	("IEEE 1149.6 standard")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14
L18	1142	(boundary scan test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14
L19	0	I17 and I18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14

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L21	3	I18 and I9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L22	2	I18 and I10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L23	13	("IEEE 1149.6")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L25	5	I23 and (I18 or I17 or I9)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:52
L26	5244	714/727 or 714/724 or 714/736 or 327/205 or 327/63 or 327/73 or 327/68	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:56
L27	3	I25 and I26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:05
L30	2	I10 and I18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:58
L32	1	I18 and (I16 or I17 or I23)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:07

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L33	1	"IEEE 1449.6 boundary scan test"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:09
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Search Query Display

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- Delete a search
- Run a search

Recent Search Queries

- | | |
|----|---|
| #1 | IEEE boundary scan test |
| #2 | ((iee 1149.6 boundary scan test)<in>metadata) <and> (pyr >= 1950 <and> pyr <= 2003) |
| #3 | ((iee 1149.6 and boundary scan test)<in>metadata) |
| #4 | ((iee 1149.6 and boundary scan test)<in>metadata) |
| #5 | ((iee 1149.6 and boundary scan test)<in>metadata) |
| #6 | ((iee 1149.6 and boundary scan test)<in>metadata) |
| #7 | ((iee 1149.6 and boundary scan test)<in>metadata) <and> (pyr >= 1950 <and> pyr <= 2003) |

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